

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	1	("6491528").PN.	USPAT; USOCR	OR	OFF	2006/10/17 17:00
L3	356	703/?ccls. and (stress\$2 and test\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/17 17:51
L4	5	I3 and (accelerat\$3 same (stress with test\$4))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/17 17:08
L5	1269	(703/2).CCLS.	USPAT; USOCR	OR	OFF	2006/10/17 17:07
L6	319	(703/7).CCLS.	USPAT; USOCR	OR	OFF	2006/10/17 17:07
L7	108	I5 and (stress\$2 and test\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/17 17:07
L8	2	I7 and (accelerat\$3 same (stress with test\$4))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/17 17:51
L9	50	I6 and (stress\$2 and test\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/17 17:51
L11	26	702/?ccls. and (stress\$3 with test\$4)	US-PGPUB; USPAT; USOCR; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/17 17:56
L12	64	73/?ccls. and (stress\$3 with test\$4)	US-PGPUB; USPAT; USOCR; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/17 17:56
L13	2	I12 and (accelerat\$4 same (test with stress))	US-PGPUB; USPAT; USOCR; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/17 17:57
L15	30424	(stress\$3 with test\$4)	US-PGPUB; USPAT	OR	ON	2006/10/17 17:58
L16	1475	(accelerat\$4 same (stress\$2 with test\$4))	US-PGPUB; USPAT	OR	ON	2006/10/17 17:59

## EAST Search History

L17	3	I16 and (MTBF or mean\$ time near2 fail\$4)	US-PGPUB; USPAT	OR	ON	2006/10/17 18:04
L18	1999	(stress with test\$3) same product	US-PGPUB; USPAT	OR	ON	2006/10/17 18:05
L19	13	I18 and (accelerat\$4 adj factor)	US-PGPUB; USPAT	OR	ON	2006/10/17 18:06
S1	7	((("6816813") or ("6684349") or ("5210704") or ("5648919") or ("5789682") or ("5949682") or ("6301970"))).PN.	USPAT; USOCR	OR	OFF	2005/07/14 14:48
S2	922	(703/2).CCLS.	USPAT; USOCR	OR	OFF	2005/07/14 08:40
S3	1	S2 and stress adj test\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 08:41
S4	0	S2 and stress same estimat\$5 same life same product\$2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 08:42
S5	24	stress same test\$5 same estimat\$5 same life same product\$2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 08:42
S6	0	stress same test\$5 same estimat\$5 same life same product\$2 same MTBF	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 08:43
S7	1	stress same test\$5 same estimat\$5 same life same product\$2 same mean adj time	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 08:43
S8	0	BOM same MTPF	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 14:49
S10	0	BOM same pervious near design	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 14:49
S11	0	Bill adj of adj material\$2 same pervious near design	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 14:50

## EAST Search History

S12	0	Bill adj of adj material\$2 same pervious near2 design	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 14:50
S13	4	((("5539652") or ("6491528") or ("6541394") or ("6546507"))). PN.	USPAT; USOCR	OR	OFF	2006/07/12 16:54

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[Preferences](#)The "AND" operator is unnecessary -- we include all search terms by default. [\[details\]](#)**Web**Results 1 - 10 of about **49,700** for **acceleration factor and MTBF**. (0.20 seconds)[\[PDF\] Reliability and MTBF Overview](#)

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**MTBF** calculations do not consider suspensions whereas MTTF does. ... use of thermal and stress **acceleration factors**, quality **factors**, use conditions. ...[www.vicr.com/documents/quality/Rel\\_MTBf.pdf](http://www.vicr.com/documents/quality/Rel_MTBf.pdf) - [Similar pages](#)[\[PDF\] Reliability and the Electronic Engineer](#)File Format: PDF/Adobe Acrobat - [View as HTML](#)Arrhenius Relationship we derive an **Acceleration Factor** of: The corrected (for finite sample size) **MTBF** with a 60%. Confidence **Factor** that we calculated ...[www.intersil.com/data/an/an1104.pdf](http://www.intersil.com/data/an/an1104.pdf) - [Similar pages](#)[\[PDF\] Why HALT Cannot Produce A Meaningful MTBF Number and Why This ...](#)File Format: PDF/Adobe Acrobat - [View as HTML](#)**(MTBF)** figures cannot be ascertained. The number of samples is low and the **acceleration factors** are not only high but varying, and this yields reliability ...[www.qualmark.com/pdf/halt\\_concerns.pdf](http://www.qualmark.com/pdf/halt_concerns.pdf) - [Similar pages](#)[\[PDF\] WHY HALT CANNOT PRODUCE A MEANINGFUL MTBF NUMBER AND WHY THIS ...](#)

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produced accurate **MTBF** numbers. Method 1 – Using HALT to Develop an RDT. The first method is using the HALT data to choose aggressive **acceleration factors** ...[www.opsalacarte.com/pdfs/Tech\\_Papers/MTBF\\_Prediction\\_HALT.pdf](http://www.opsalacarte.com/pdfs/Tech_Papers/MTBF_Prediction_HALT.pdf) - [Similar pages](#)[Electronic Component engineering - MTBF Degradation of CPU's After ...](#)I am seeking reliability White Papers or other relevant info on **MTBF** ... If the **acceleration factor** is 10x per 10 degC, then a 50 degC increase in temp ...[www.eng-tips.com/gviewthread.cfm/lev2/11/lev3/47/pid/797/qid/35348](http://www.eng-tips.com/gviewthread.cfm/lev2/11/lev3/47/pid/797/qid/35348) - 30k -[Cached](#) - [Similar pages](#)[\[PDF\] TN-00-18 Uprating Semiconductors for High-Temperature Applications](#)File Format: PDF/Adobe Acrobat - [View as HTML](#)The Arrhenius equation is used to calculate an **acceleration factor** for the ... Figure 2 shows the relationship between temperature and **MTBF** for a ...[download.micron.com/pdf/technotes/TN0018.pdf](http://download.micron.com/pdf/technotes/TN0018.pdf) - [Similar pages](#)[\[PDF\] AN5028-3 b.fm](#)File Format: PDF/Adobe Acrobat - [View as HTML](#)rate and relates more to the Reliability function and **MTBF**. ... The **acceleration factor** is a constant used in the reliability ...[www.ams.aeroflex.com/ProductFiles/AppNotes/RDCRelApNote.pdf](http://www.ams.aeroflex.com/ProductFiles/AppNotes/RDCRelApNote.pdf) - [Similar pages](#)[\[PDF\] WHY HALT CANNOT PRODUCE A MEANINGFUL MTBF NUMBER AND WHY THIS ...](#)File Format: PDF/Adobe Acrobat - [View as HTML](#)Time Between Failure (**MTBF**) figures cannot be ascertained. The number of samples is low, and the **acceleration factors** are not only high but varying, ...[www.hobbsengr.com/papers/MTBF\\_Paper.pdf](http://www.hobbsengr.com/papers/MTBF_Paper.pdf) - [Similar pages](#)[Electronics Cooling: how to evaluate fan life](#)

The **MTBF** should only be used in a repairable systems setting. ... Therefore, applying these **acceleration factors** down to a room temperature of 25°C is ...

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The **acceleration factor** depends mainly on the exposed. temperature for both semiconductors and ... **MTBF** = 200 years is a high reliability figure compared ...

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Best 200 shown

Relevance scale ☐ ☐ ☐ ☐ ☐**1** [Collision detection and proximity queries](#) Sunil Hadap, Dave Eberle, Pascal Volino, Ming C. Lin, Stephane Redon, Christer Ericson  
August 2004 **ACM SIGGRAPH 2004 Course Notes SIGGRAPH '04****Publisher:** ACM PressFull text available: pdf(11.22 MB) Additional Information: [full citation](#), [abstract](#)

This course will primarily cover widely accepted and proved methodologies in collision detection. In addition more advanced or recent topics such as continuous collision detection, ADFs, and using graphics hardware will be introduced. When appropriate the methods discussed will be tied to familiar applications such as rigid body and cloth simulation, and will be compared. The course is a good overview for those developing applications in physically based modeling, VR, haptics, and robotics.

**2** [Accelerating XPath evaluation in any RDBMS](#) Torsten Grust, Maurice Van Keulen, Jens Teubner  
March 2004 **ACM Transactions on Database Systems (TODS)**, Volume 29 Issue 1**Publisher:** ACM PressFull text available: pdf(781.01 KB) Additional Information: [full citation](#), [abstract](#), [references](#), [index terms](#)

This article is a proposal for a database index structure, the *XPath accelerator*, that has been specifically designed to support the evaluation of XPath path expressions. As such, the index is capable to support *all* XPath axes (including ancestor, following, preceding-sibling, descendant-or-self, etc.). This feature lets the index stand out among related work on XML indexing structures which had a focus on the child and descendant axes only. The index has been designed with a close ...

**Keywords:** Main-memory databases, XML, XML indexing, XPath**3** [Distributional Scaling: An Algorithm for Structure-Preserving Embedding of Metric and Nonmetric Spaces](#)Michael Quist, Golan Yona  
December 2004 **The Journal of Machine Learning Research**, Volume 5**Publisher:** MIT PressFull text available: pdf(508.39 KB) Additional Information: [full citation](#), [abstract](#), [references](#), [index terms](#)

We present a novel approach for embedding general metric and nonmetric spaces into low-dimensional Euclidean spaces. As opposed to traditional multidimensional scaling

techniques, which minimize the distortion of pairwise distances, our embedding algorithm seeks a low-dimensional representation of the data that preserves the structure (geometry) of the original data. The algorithm uses a hybrid criterion function that combines the pairwise distortion with what we call the geometric distortion. T ...

#### 4 Level set and PDE methods for computer graphics



David Breen, Ron Fedkiw, Ken Museth, Stanley Osher, Guillermo Sapiro, Ross Whitaker  
August 2004 **ACM SIGGRAPH 2004 Course Notes SIGGRAPH '04**

**Publisher:** ACM Press

Full text available: pdf(17.07 MB) Additional Information: [full citation](#), [abstract](#), [citations](#)

Level set methods, an important class of partial differential equation (PDE) methods, define dynamic surfaces implicitly as the level set (iso-surface) of a sampled, evolving nD function. The course begins with preparatory material that introduces the concept of using partial differential equations to solve problems in computer graphics, geometric modeling and computer vision. This will include the structure and behavior of several different types of differential equations, e.g. the level set eq ...

#### 5 Facial modeling and animation



Jörg Haber, Demetri Terzopoulos  
August 2004 **ACM SIGGRAPH 2004 Course Notes SIGGRAPH '04**

**Publisher:** ACM Press

Full text available: pdf(18.15 MB) Additional Information: [full citation](#), [abstract](#)

In this course we present an overview of the concepts and current techniques in facial modeling and animation. We introduce this research area by its history and applications. As a necessary prerequisite for facial modeling, data acquisition is discussed in detail. We describe basic concepts of facial animation and present different approaches including parametric models, performance-, physics-, and learning-based methods. State-of-the-art techniques such as muscle-based facial animation, mass-s ...

#### 6 The elements of nature: interactive and realistic techniques



Oliver Deussen, David S. Ebert, Ron Fedkiw, F. Kentoń Musgrave, Przemyslaw Prusinkiewicz, Doug Roble, Jos Stam, Jerry Tessendorf  
August 2004 **ACM SIGGRAPH 2004 Course Notes SIGGRAPH '04**

**Publisher:** ACM Press

Full text available: pdf(17.65 MB) Additional Information: [full citation](#), [abstract](#)

This updated course on simulating natural phenomena will cover the latest research and production techniques for simulating most of the elements of nature. The presenters will provide movie production, interactive simulation, and research perspectives on the difficult task of photorealistic modeling, rendering, and animation of natural phenomena. The course offers a nice balance of the latest interactive graphics hardware-based simulation techniques and the latest physics-based simulation techni ...

#### 7 Session 4D: Model order reduction: A trajectory piecewise-linear approach to model order reduction and fast simulation of nonlinear circuits and micromachined devices

Michał Rewieński, Jacob White

November 2001 **Proceedings of the 2001 IEEE/ACM international conference on Computer-aided design**


**Publisher:** IEEE Press

Full text available: pdf(180.34 KB) Additional Information: [full citation](#), [abstract](#), [references](#), [citations](#), [index terms](#)

In this paper we present an approach to the nonlinear model reduction based on representing the nonlinear system with a piecewise-linear system and then reducing each

of the pieces with a Krylov projection. However, rather than approximating the individual components as piecewise-linear and then composing hundreds of components to make a system with exponentially many different linear regions, we instead generate a small set of linearizations about the state trajectory which is the response to a ...

### 8 A systems analysis of stress-strain in VDT operation

 Steven L. Sauter, Mark S. Gottlieb, Karen C. Jones  
March 1982 **Proceedings of the 1982 conference on Human factors in computing systems**

**Publisher:** ACM Press

Full text available:  [pdf\(442.09 KB\)](#) Additional Information: [full citation](#), [abstract](#), [references](#), [index terms](#)

The last half decade has witnessed a rapidly accelerating trend toward the application of video display terminal (VDT) technology for information management in the office workplace, and a growing body of scientific and anecdotal data on the implications of VDT use for the well-being of office workers [2,4,6-8,11,15,16]. A striking aspect of the research on this subject is the degree of conflict among reports regarding the type, magnitude, and causes of adverse changes in the health, comfort ...


### 9 Nearly linear time algorithms for permutation groups with a small base

 László Babai, Gene Cooperman, Larry Finkelstein, Ákos Seress  
June 1991 **Proceedings of the 1991 international symposium on Symbolic and algebraic computation**


**Publisher:** ACM Press

Full text available:  [pdf\(1.19 MB\)](#) Additional Information: [full citation](#), [references](#), [citations](#), [index terms](#)

### 10 Spherical averages and applications to spherical splines and interpolation

 Samuel R. Buss, Jay P. Fillmore  
April 2001 **ACM Transactions on Graphics (TOG)**, Volume 20 Issue 2

**Publisher:** ACM Press

Full text available:  [pdf\(214.52 KB\)](#) Additional Information: [full citation](#), [abstract](#), [references](#), [citations](#), [index terms](#)

This article introduces a method for computing weighted averages on spheres based on least squares minimization that respects spherical distance. We prove existence and uniqueness properties of the weighted averages, and give fast iterative algorithms with linear and quadratic convergence rates. Our methods are appropriate to problems involving averages of spherical data in meteorological, geophysical, and astronomical applications. One simple application is a method for smooth averaging of quat ...

**Keywords:** Bézier curve, B-spline, barycentric coordinates, least squares minimization, quaternion interpolation, quaternions, spherical average, spherical interpolation, spherical mean, spline curve, spline interpolation

### 11 Computing curricula 2001

 September 2001 **Journal on Educational Resources in Computing (JERIC)**

**Publisher:** ACM Press

Full text available:  [pdf\(613.63 KB\)](#)  [html\(2.78 KB\)](#) Additional Information: [full citation](#), [references](#), [citations](#), [index terms](#)


### 12

Three-dimensional medical imaging: algorithms and computer systems



 M. R. Stytz, G. Frieder, O. Frieder  
December 1991 **ACM Computing Surveys (CSUR)**, Volume 23 Issue 4

**Publisher:** ACM Press

Full text available:  pdf(7.38 MB)

Additional Information: [full citation](#), [references](#), [citations](#), [index terms](#), [review](#)

**Keywords:** Computer graphics, medical imaging, surface rendering, three-dimensional imaging, volume rendering

### 13 Nonconvex rigid bodies with stacking

 Eran Guendelman, Robert Bridson, Ronald Fedkiw  
July 2003 **ACM Transactions on Graphics (TOG)**, Volume 22 Issue 3

**Publisher:** ACM Press

Full text available:  pdf(5.19 MB)

Additional Information: [full citation](#), [abstract](#), [references](#), [citations](#), [index terms](#)

We consider the simulation of nonconvex rigid bodies focusing on interactions such as collision, contact, friction (kinetic, static, rolling and spinning) and stacking. We advocate representing the geometry with both a triangulated surface and a signed distance function defined on a grid, and this dual representation is shown to have many advantages. We propose a novel approach to time integration merging it with the collision and contact processing algorithms in a fashion that obviates the need ...

**Keywords:** collision, contact, friction, nonconvex, rigid bodies

### 14 Special section: Reasoning about structure, behavior and function

 B. Chandrasekaran, Rob Milne  
July 1985 **ACM SIGART Bulletin**, Issue 93


**Publisher:** ACM Press

Full text available:  pdf(5.13 MB)

Additional Information: [full citation](#), [abstract](#), [references](#)

The last several years' of work in the area of knowledge-based systems has resulted in a deeper understanding of the potentials of the current generation of ideas, but more importantly, also about their limitations and the need for research both in a broader framework as well as in new directions. The following ideas seem to us to be worthy of note in this connection.

### 15 Numerical computations: its nature and research directions

 J. R. Rice, C. W. Gear, J. Ortega, B. Parlett, M. Schultz, L. F. Shampine, P. Wolfe, J. F. Traub  
February 1979 **ACM SIGNUM Newsletter**, Volume 14 Issue si-1


**Publisher:** ACM Press

Full text available:  pdf(4.43 MB)

Additional Information: [full citation](#), [abstract](#), [references](#)

This report on research in numerical computation is part of the Computer Science and Engineering Research Study (COSERS) which is aimed at technically educated people outside the Computer Science field. This goal led the panel to face many difficult choices between precise, but excessively technical, descriptions and looser, but more accessible expositions. The panel hopes that all readers will keep this in mind.

### 16 ABSTRACTS OF INTEREST

 Susanne M. Humphrey, Ben Shneiderman  
July 1987 **ACM SIGCHI Bulletin**, Volume 19 Issue 1

**Publisher:** ACM Press

Full text available:  pdf(948.57 KB) Additional Information: [full citation](#), [abstract](#)

The following abstracts were selected from a computer search, using the BRS Information Technologies retrieval services, of the Dissertation Abstracts international (DAI) database produced by University Microfilms International. Unless otherwise specified, paper or microform copies of dissertations may be ordered, using the UM order number, from University Microfilms International, Dissertation Copies, Post Office Box 1764, Ann Arbor, MI 48106; telephone for U.S. (except Michigan, Hawaii or Alaska ...

17 Graph mining: Laws, generators, and algorithms



Deepayan Chakrabarti, Christos Faloutsos

June 2006 **ACM Computing Surveys (CSUR)**, Volume 38 Issue 1

**Publisher:** ACM Press

Full text available:  pdf(910.68 KB) Additional Information: [full citation](#), [abstract](#), [references](#), [index terms](#)

How does the Web look? How could we tell an abnormal social network from a normal one? These and similar questions are important in many fields where the data can intuitively be cast as a graph; examples range from computer networks to sociology to biology and many more. Indeed, any  $M : N$  relation in database terminology can be represented as a graph. A lot of these questions boil down to the following: "How can we generate synthetic but realistic graphs?" To answer thi ...

**Keywords:** Generators, graphs, patterns, social networks


18 Shape-based retrieval and analysis of 3D models



Thomas Funkhouser, Michael Kazhdan

August 2004 **ACM SIGGRAPH 2004 Course Notes SIGGRAPH '04**

**Publisher:** ACM Press

Full text available:  pdf(12.56 MB) Additional Information: [full citation](#), [abstract](#)

Large repositories of 3D data are rapidly becoming available in several fields, including mechanical CAD, molecular biology, and computer graphics. As the number of 3D models grows, there is an increasing need for computer algorithms to help people find the interesting ones and discover relationships between them. Unfortunately, traditional text-based search techniques are not always effective for 3D models, especially when queries are geometric in nature (e.g., find me objects that fit into thi ...

19 Information systems curriculum recommendations for the 80s: undergraduate and graduate programs



Jay F. Nunamaker, J. Daniel Cougar, Gordon B. Davis

November 1982 **Communications of the ACM**, Volume 25 Issue 11

**Publisher:** ACM Press

Full text available:  pdf(2.20 MB) Additional Information: [full citation](#), [abstract](#), [references](#), [citations](#), [index terms](#)

The recommendations of the 1972 and 1973 ACM Curriculum Committee on Information Systems programs have been influential in the development of degree programs at the bachelor's, master's, and doctoral levels. The earlier curriculum has been revised and updated based on advances in the field over the past nine years. The report discusses the continuing need for education related to the definition, analysis, design, construction, and management of information systems in organizations. The stru ...

20 Job and health implications of VDT use: initial results of the Wisconsin-NIOSH study

Steven L. Sauter, Mark S. Gottlieb, Karen C. Jones, Vernon N. Dodson, Kathryn M. Rohrer



April 1983 **Communications of the ACM**, Volume 26 Issue 4

**Publisher:** ACM Press

Full text available: pdf(1.09 MB)

Additional Information: [full citation](#), [abstract](#), [references](#), [citations](#), [index terms](#)

Magnitudes and correlates of stress were investigated among 248 office workplace VDT users and 85 nonuser counterparts using field survey and objective physical measurement techniques. Other than a tenuous indication of increased eyestrain and reduced psychological disturbances among users, the two groups were largely undifferentiated on job-attitudinal, affective, and somatic manifestations of stress. However, aspects of working conditions were judged less favorably by VDT users. S ...

**Keywords:** ergonomics, health, human factors, occupational stress, office automation, video display terminals (VDTs, CRTS)

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☒ **4. Accelerated stress testing in a time-driven product development process**

 Lu, Y. / Loh, H.T. / Brombacher, A.C. / Ouden, E.d., *International Journal of Production Economics*, Aug 2000

...Elsevier Science B.V. **Accelerated stress testing** in a time-driven product...classical solution is to use **accelerated stress testing (AST)** to

find reliability...time-driven PDP. 2 Classical **accelerated stress testing** strategies 2.1 Generic...

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...Pocket Geometry for **Stress** Analysis of Optical...Thermo-Mechanical **Stress** Distribution in Plated-Through-Hole...Identification in **Accelerated Testing**," Journal of the Institute...A., "A Fractional-**Factorial** Numerical Technique...Actuators and Sensors for **Accelerated Stress Testing** and Health Monitoring...

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☐ 6. [The Arrhenius, Eyring, inverse power law and combination models in accelerated life testing](#)

**Kececioglu, D. / Jacks, J.A.**, *Reliability Engineering*, Jan 1984

...LTu) (7) The acceleration **factor** in **accelerated life testing** is given by

$AF = LTu/LTA \dots 33\ 000\ h$  The acceleration **factor** is found, from eqn.

$(9 \dots 423) \dots = 12\ 3$  EYRING SINGLE **STRESS** MODEL The Eyring model also uses temperature as the **accelerated** variable. It is derived from...

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☐ 7. [Thermal characterization of LDMOS transistors for accelerating stress testing](#)

**Bosc, J.M. / Dupuy, P. / Gil, J. / Dorkel, J.M. / Sarraayrouse, G.**, *Microelectronics Journal*, Oct 2000

...**accelerated stress testing** (AST) in order to...industry Multi-pulse **testing** Energy pulse characterization...includes setting up **accelerated** reliability tests...accurately duplicate the **stress** on the device in...becomes the limiting **factor** in power device design...**testing**. 6 Multi-pulse **testing** We want to duplicate...high acceleration **factor** the thermal cycling...parameters of an accurate **accelerated stress** test (AST). Fig...

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...ALPHA PARTICLE SENSITIVITY (**ACCELERATED** SOFT-ERROR) **STRESS TESTING**...APPENDIX B: TEMPERATURE CYCLING **STRESS** TEST MODELS...EQUIVALENCE OF DIFFERENT **STRESS** TEST CONDITIONS...TEMPERATURE HUMIDITY BIAS **TESTING**..... 35 APPENDIX H: VOLTAGE ACCELERATION **FACTORS**...

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...2000 6 Acceleration **Testing** · The failure rate...inherently low. · Elevated **stresses** are used to produce...The objective of this **testing** is to identify these...product. · Acceleration **factors** are used by device...based on the results of **accelerated testing**. HTOL - Temp (Tt...Mechanisms Applied **Stress** TEST Temperature Humidity...

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...**factors** contribute to What **factors** contribute to semiconductor...failures: · Thermal/mechanical **stress**. Thermal/mechanical **stress**...and reliability? · The **testing** of semiconductor devices is The **testing** of semiconductor devices...voltage/high temperature **stress**) is used to accelerate the...processes is monitored through **accelerated testing**. monitored through...

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☐ 11. [A proposed stress history for fatigue testing applicable to offshore structures](#)

**Hartt, W.H. / Lin, N.K.**, *International Journal of Fatigue*, Apr 1986

...into one and raising the **stress** level. The test time history...fatigue spectrum loading **accelerated testing** offshore structures The problems...simulating loads in a laboratory **testing** or research programme are...includes extreme, infrequent **stress** excursions which may be important...offshore struc- tures the above **factors** may be compounded by the...

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☐ 12. [A comparison between normally and highly accelerated electromigration tests](#)

**Foley, S. / Scorzoni, A. / Balboni, R. / Impronta, M. / De Munari, I. / Mathewson, A. / Fantini, F.**, *Microelectronics and Reliability*, Jun 1998

...Abstract Normally and highly **accelerated** electromigration tests on...depending on the range of **stress** conditions considered. It...only in the case of normally **accelerated stress** conditions (temperatures...current density acceleration **factor** is 2. i) 1998 Elsevier Science...achieved by using very highly **accelerated stress** conditions. The first...

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...processes is monitored through **accelerated testing**. monitored through **accelerated testing**. Thermal Acceleration **Factor** Thermal Acceleration **Factor** Where:  $T_s = \text{Accelerated Stress Temperature in Kelvins}$   $T_o = \text{Typical Operating Temperature in Kelvins}$ ...

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☐ **16. Experiment design and graphical analysis for checking acceleration models**

**Luvalle, M.J.**, *Microelectronics Reliability*, Apr 1993

...The purpose of **accelerated life testing** (ALT) is to shorten...the acceleration **factor** is the scaling...the acceleration **factor**. One analytical...in plots of the **stress** function against...1) Introduction **Accelerated** life tests potentially...the accelerating **stresses** are affecting the...on **accelerated testing** [1]. The arguments...

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...are as follows: (1) **stress testing** of the drug substance...frequency was amended for **accelerated testing** conditions...nature of the **stress testing** will depend on the...drug product involved. **Stress testing** is likely to be carried...C) above that for **accelerated testing**), humidity...

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☐ **20. The weibull stress-life, log-log stress-life, and the overload-stress reliability models in accelerated life testing**

**Kececioglu, D. / Jacks, J.A.**, *Reliability Engineering*, Jan 1985

...average reliability at **accelerated stress** is calculated from...20 +2 and from prior **testing**. Since the umts are tested at overload **factor** is  $m = -1/6$  15~ overload...or no-overload (NW). **stress** level from eqn (11...combmauon models m **accelerated life testing**, Reliab Engng, 8(1...

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